



## HOMMEL-ETAMIC T8000 RC

### Combined roughness and contour measurement

- Traverse unit with high straightness accuracy, high resolution, exact positioning and bi-directional measuring
- Solid and robust motorized measuring column for exact positioning and precise measurement results in every position
- Accessories for different applications included
- Innovative, user-friendly evaluation software for roughness and contour with menu-guided operation
- CNC software option for automated measuring runs



Precision is our business.



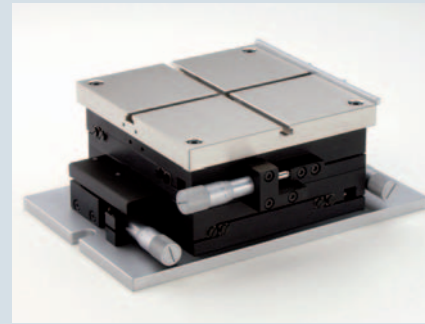
Calibration set  
wavecontour digital



Roughness standard  
RNDH2



Pick-up set TKU



Measuring table MT1

## HOMMEL-ETAMIC T8000 Roughness and Contour

T8000 RC120-400	Art. 1001 7070
T8000 RC120-400 L	Art. 1001 7071
T8000 RC120-800 L	Art. 1001 7072

### Standard equipment

- Evaluation unit with 19" TFT flat screen, color printer, CD-writer
- Evaluation software for roughness and contour
- Measuring column wavelift with motorized height adjustment and 0.1-12 mm/s traverse speed: max. traverse 400/800 mm
- Traverse unit waveline 120 advanced with linear encoder and 0.1  $\mu\text{m}$  resolution; tracing length 120 mm; straightness accuracy < 0.4  $\mu\text{m}/120\text{ mm}$
- Tilting unit for traverse unit with coarse adjustment range  $\pm 45^\circ$  and fine adjustment range  $\pm 5^\circ$
- Granite plate with 10 mm T-slot:  
780 x 500 or 1000 x 500 mm
- Pick-up set TKU with 4 tracing arms
- Pick-up holder FHZ
- Roughness standard RNDH2 with Ra approx. 1  $\mu\text{m}$  and Rz approx. 3  $\mu\text{m}$
- Contour pick-up wavecontour digital with tracing arm and hard metal tip TA-60; measuring strike 60 mm; linear encoder, 0.05  $\mu\text{m}$  resolution
- Calibration set wavecontour digital
- Measuring table MT1 for part positioning

### Parameters

Roughness parameters EN ISO 4287	Ra; Rz; Rmax; Rt; Rq; Rsk; lmo; lo; Rdq; da; ln; La; Lq; Rz-ISO; R3z; Rpm, Rp3z; R3zm; Rp; D; RPC; RSm; Rpm/R3z; lr; Rku; tpif; Rdc; tpia; tpip; tpic; Rt/Ra; Rz1; Rz2; Rz3; Rz4; Rz5; Rmr; Rmr%; Api
Rk parameters EN ISO 13565	Rpk*; Rpk; Rk; Rvk*; Rvk; Mr1; Mr2; A1; A2; Vo (70 %); 1,01*; Rv/Rk
Profile parameters EN ISO 4287	Pt'; Pp; Pz; Pa; Pq; Psk; PSm; Pdq; lp; Pku; tpaf; tpa; tpab; tpac; Pmr0; APa; APa%; Pmr; Pmr%; Pdc
Waviness parameters EN ISO 4287	Wt'; Wp; Wz; Wa; Wq; Wsk; WSm; Wdq; lw; Wku; Wdc
Waviness parameters VDA 2007	WD1c; WD1t; WD1sm; WD2c; WD2t; WD2sm
Motif parameters EN ISO 12085	R; Rx; AR; Nr; W; Wx; AW; Nw; Wte; Tpa (CR, CL, CF)
Roughness parameters JIS B-0601	Rz-JIS; WCA; WCM
Contour measurement	Point, straight line, radius, angle, min-max function, X distances, Z distances, radii comparison, aligning, base formation, profile fit, measuring report specification, nominal-actual comparison, convexity measurement, statistics SPC, rotation and translation of the profiles and many more